Search Notes

Application/Control No.	Applicant(s)/Patent Reexamination		
10/710,745	BONACCIO ET AL	•	
Examiner	Art Unit		
Henry K. Choe	2817		

OF A DOUGH					
	SEARCHED				
Class	Subclass	Date	Examiner		
33-	258	11/7/05	H-c.		
1	253	(1	(1		
١,	259	٠,	• •		
, ,	257		``		
· 1	260	11/8/05	٠,		
,1	26/	/ /	`1		
upsate	Saul	1/4/06	71		
V		•			

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
Sean	of ofor	e 1/5/a	of Hic			
see	attack	Rmat				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Tal sil (East) See attochust NY	11/9/00	F 4.c,
NY (IEEE) See attachment	/1	/1